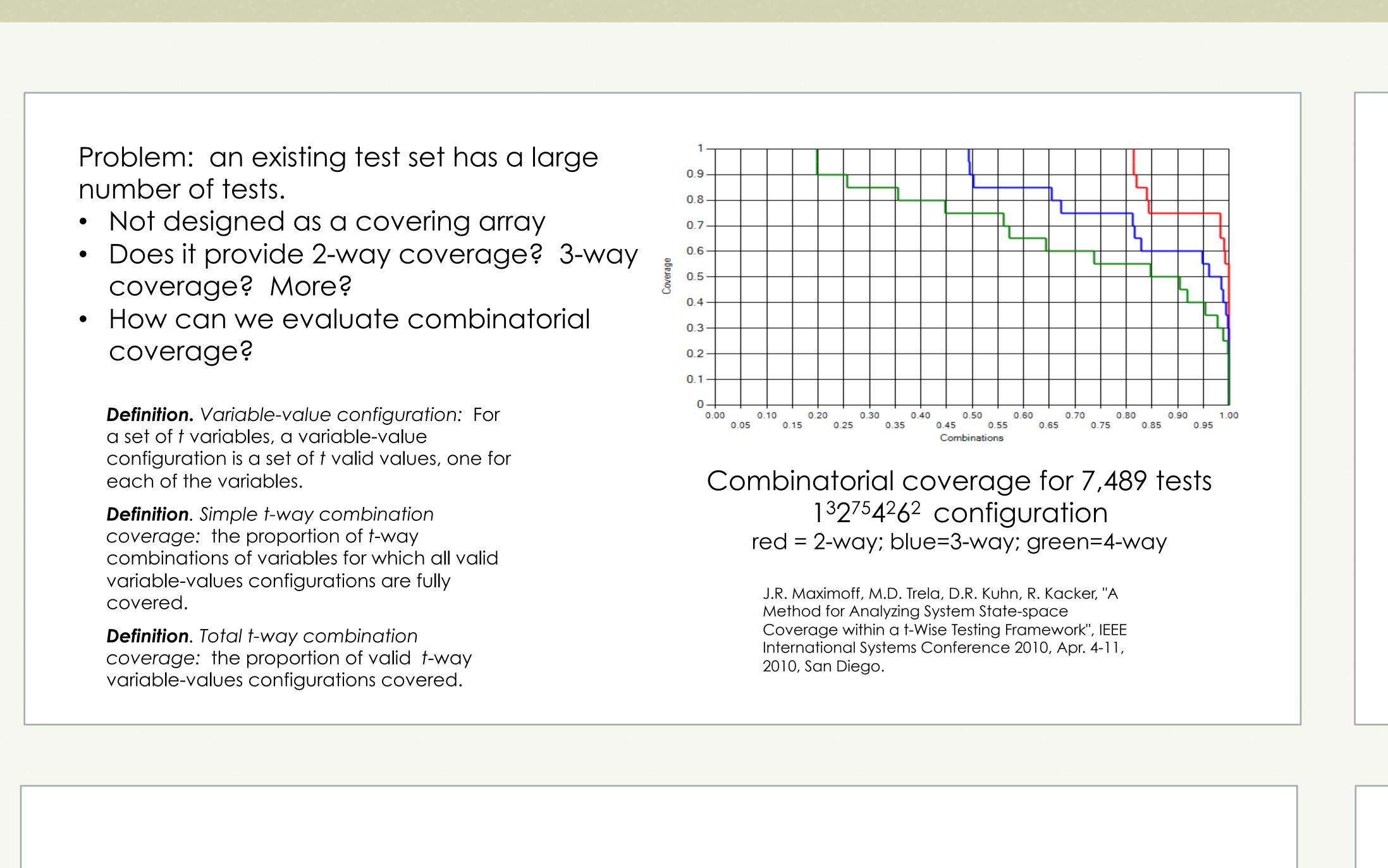
Combinatorial Coverage as an Estimator of Residual Risk After Testing Dimitris E. Simos¹, Kristoffer Kleine¹, Rick Kuhn², Raghu Kacker²

¹SBA Research , Vienna, Austria {dsimos, kkleine}@sba-research.org



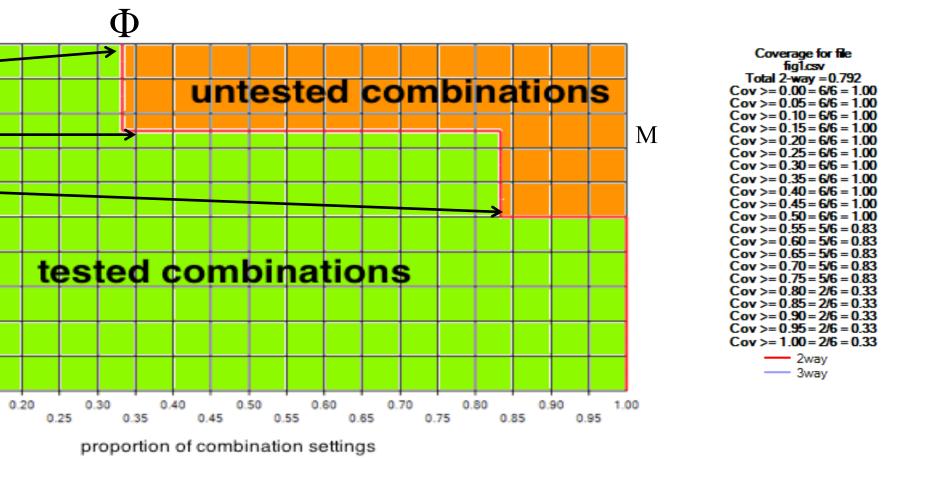
Test #	a	b	С	d
1	0	0	0	0
2	0	1	1	0
3	1	0	0	1
4	0	1	1	1

Vars	Configurations covered	Config coverage
ab	00, 01, 10	.75
ас	00, 01, 10	.75
ad	00, 01, 11	.75
bc	00, 11	.50
bd	00, 01, 10, 11	1.0
сd	00, 01, 10, 11	1.0

2/6 covered to 100% 3/6 covered to 75% ⁻ 6/6 covered to $\geq 50\%$ total 2-way coverage = 19/24 = .79(area under curve)

• Tests contain four binary variables: a, b, c, d • What can we say about coverage?

- Tests have $\binom{4}{2}$ 2-way combinations with 4 values each: 00, 01, 10, 11
- Measure the coverage of each combination
- $\Phi = \%$ of combinations w/ full 100% value coverage
- M = minimum value coverage



Evaluating Test Strategies

- Combinatorial coverage is an important consideration for all test strategies
- Helps us understand why some strategies are effective

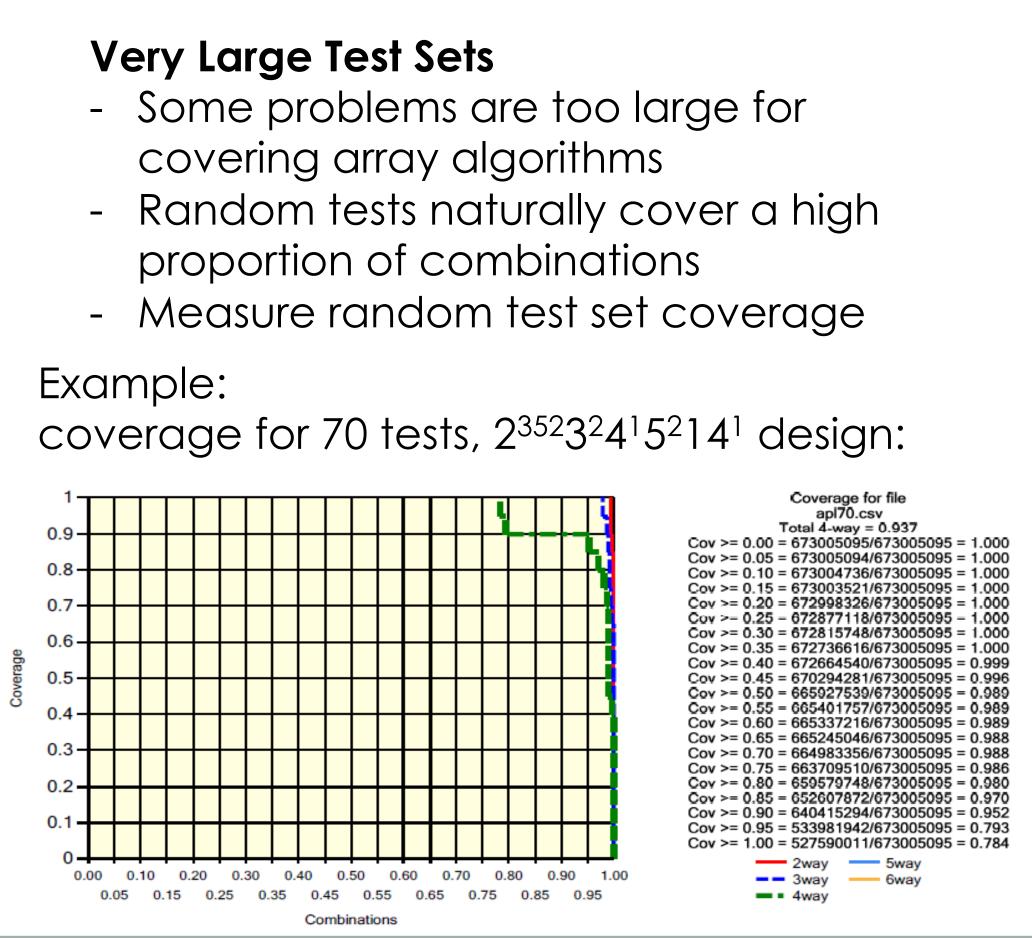
Some properties of test criteria

 M_t (all-values) $\geq \frac{1}{v^{t-1}}$

 M_t (base-choice) = $\frac{1+t(v-1)}{t}$

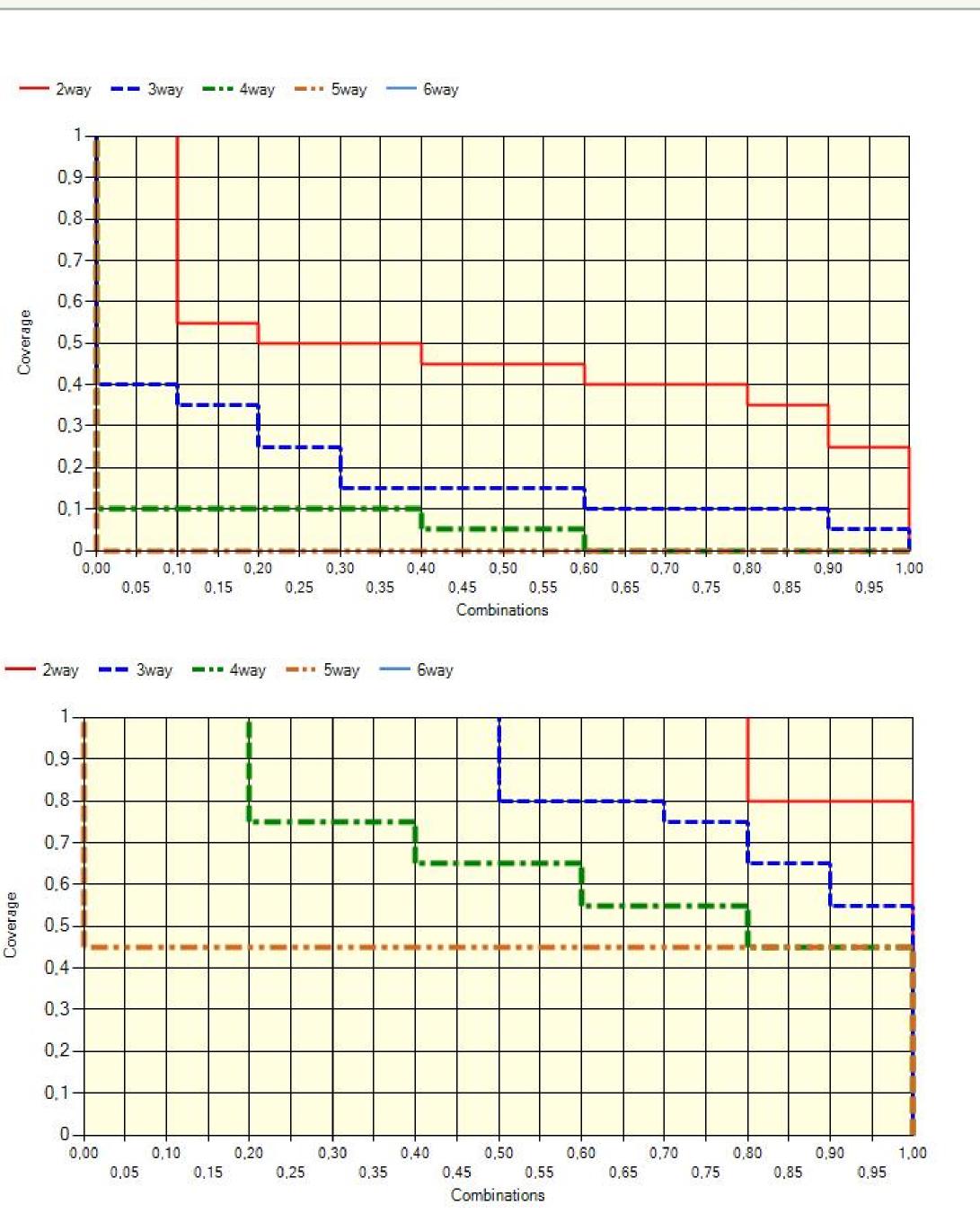
(t+1)-way total coverage: $S_{t+1} \ge 1/v$

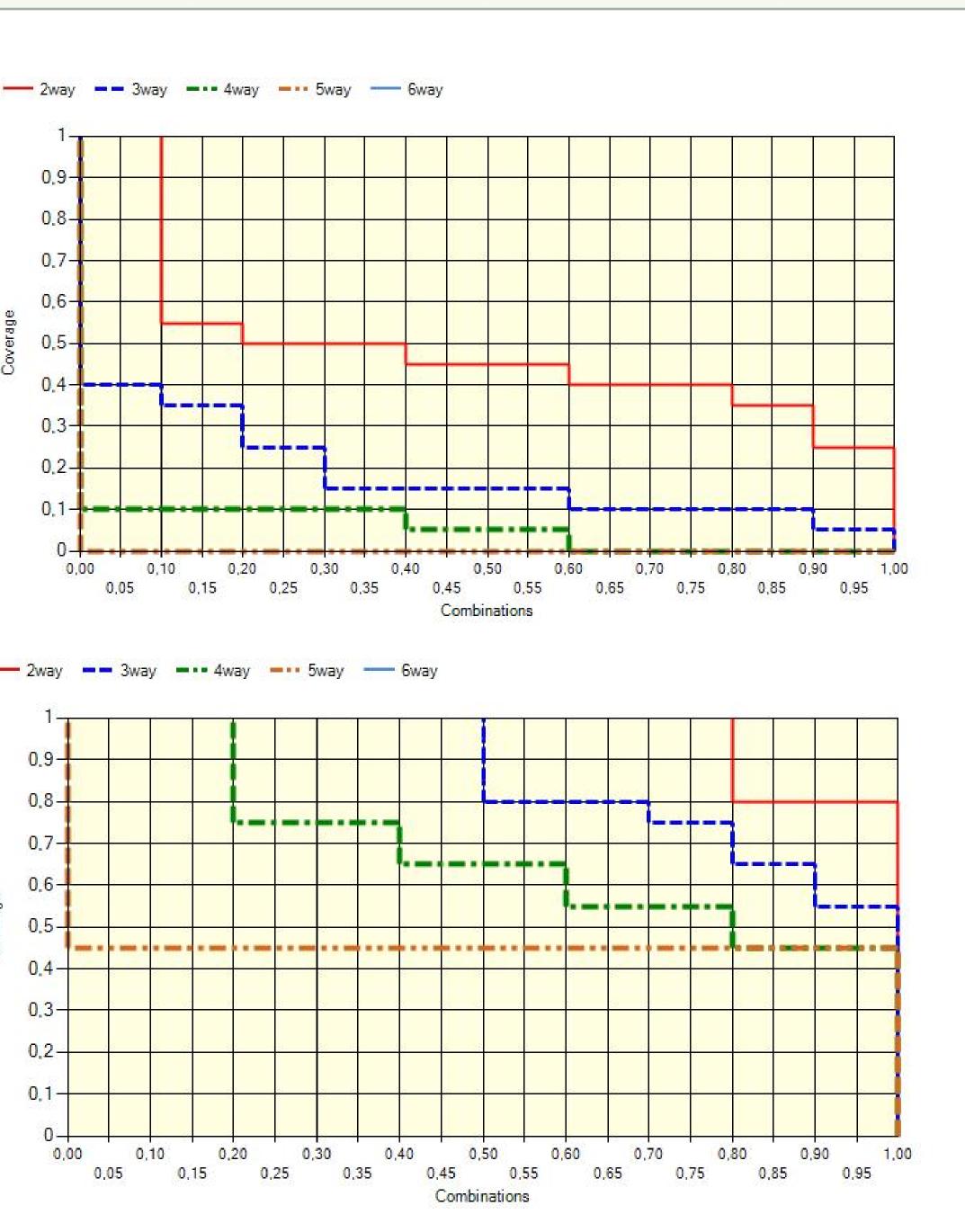
 S_t = total variable-value coverage, the proportion of variable-value configurations that are covered by at least one test M_t = minimum coverage of *t*-way settings among combinations



MEASURING TLS CIPHER SUITES

- combination of key exchange, authentication, encryption and MAC algorithms
- interactions between components may be sources of problems
- useful to consider what interactions exist in already implemented code; what may need more extensive testing if suite is extended
- Examples
 - IANA input model of $5^{1}6^{2}10^{1}28^{1} = 8400$ possible implementations; small proportion covered
 - Mozilla smaller input model; larger proportion covered
- Combinatorial coverage provides a measure of one aspect of assurance complexity





² Natl Inst of Standards & Technology, USA {kuhn,raghu.kacker}@nist.gov